## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination CHEN ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,493,682	02-1996	Tyra et al.	717/122
*	В	US-4,989,132	01-1991	Mellender et al.	717/139
*	С	US-6,249,905	06-2001	Yoshida et al.	717/100
*	D	US-52,109 A1	01-1866	Nagashima et al.	416/72
*	E	US-6,557,165 B1	04-2003	Nagashima et al.	717/108
*	F	US-5,864,862	01-1999	Kriens et al.	707/103R .
*	G	US-5,437,027	07-1995	Bannon et al.	707/103R
*	Н	US-5,297,279	03-1994	Bannon et al.	707/103R
*	1	US-6,377,951	04-2002	Campbell, R. David L.	707/10
*	J	US-5,758,160	05-1998	McInerney et al.	717/104
*	К	US-2004/0015831	01-2004	Bowhill, Allan J.C.	717/106
*	L	US-5,694,596	12-1997	Campbell, R. David L.	707/10
*	М	US-5,937,405	08-1999	Campbell, R. David L.	707/10

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 2001/31439	05-2001	USA	Method and Apparatus for	
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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	<b>V</b>							
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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